Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/593,004	ANDO, TOMOYUKI
Examiner	Art Unit
Sin J. Lee	1795

SEARCHED					
Class	Subclass	Date	Examiner		

Class	Subclass	Date	Examiner
			+
			-

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
,	DATE	EXMR		
EIC structure search	2/28/2009	SJL		